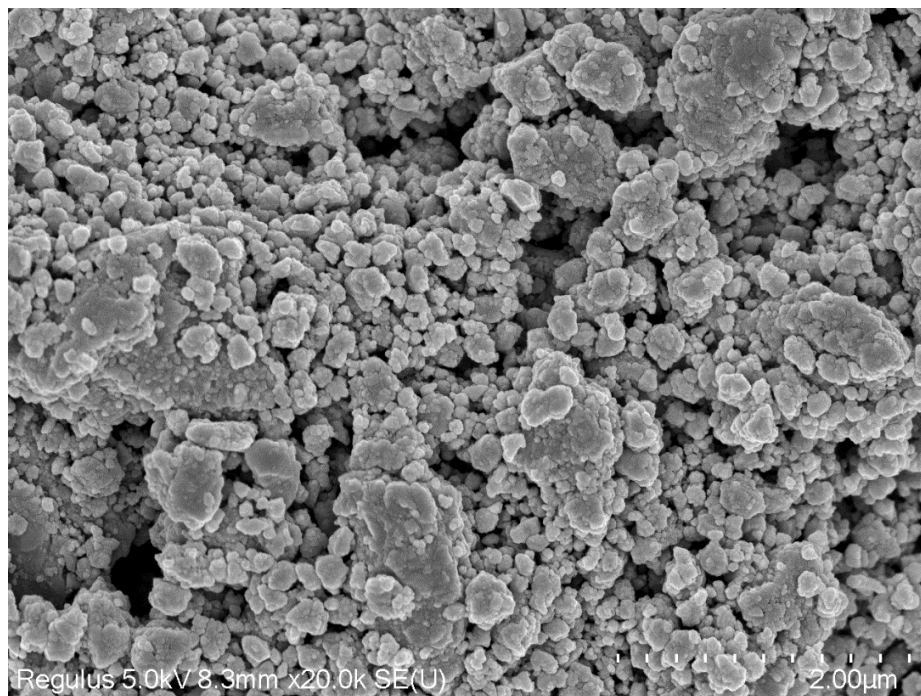


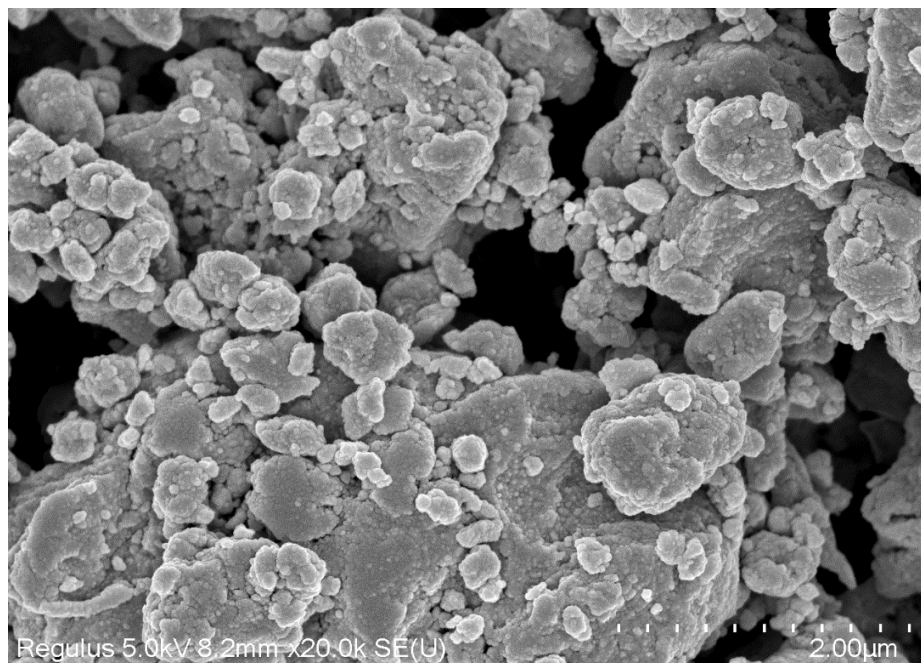
## Supplementary Materials

### 2.2.2. Scanning Electron Microscopy of a film surface

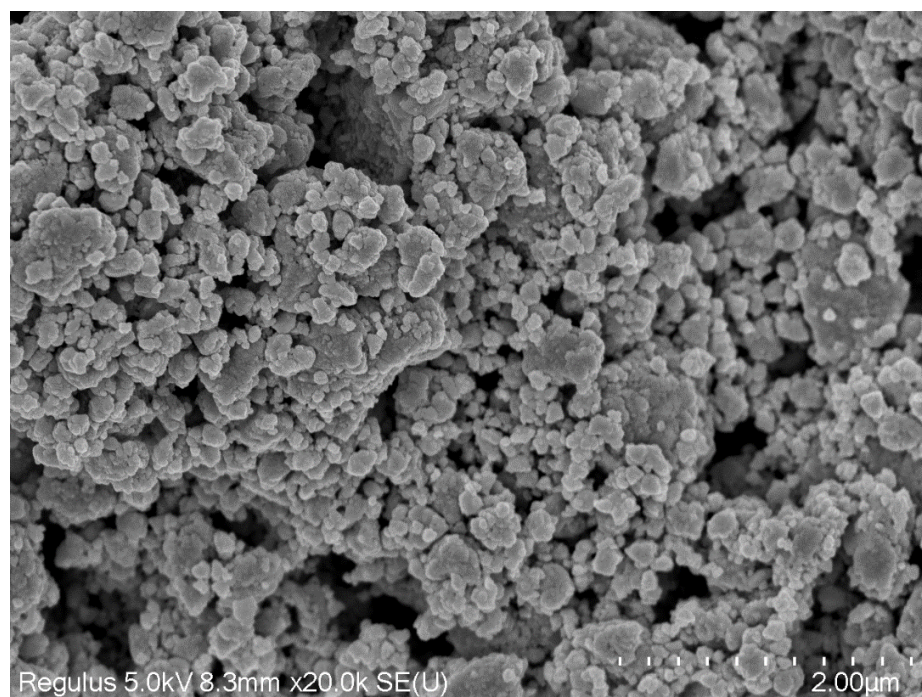
The following SEM images were acquired using a Hitachi Regulus 8220 Scanning Electron Microscope (Mito, Japan).



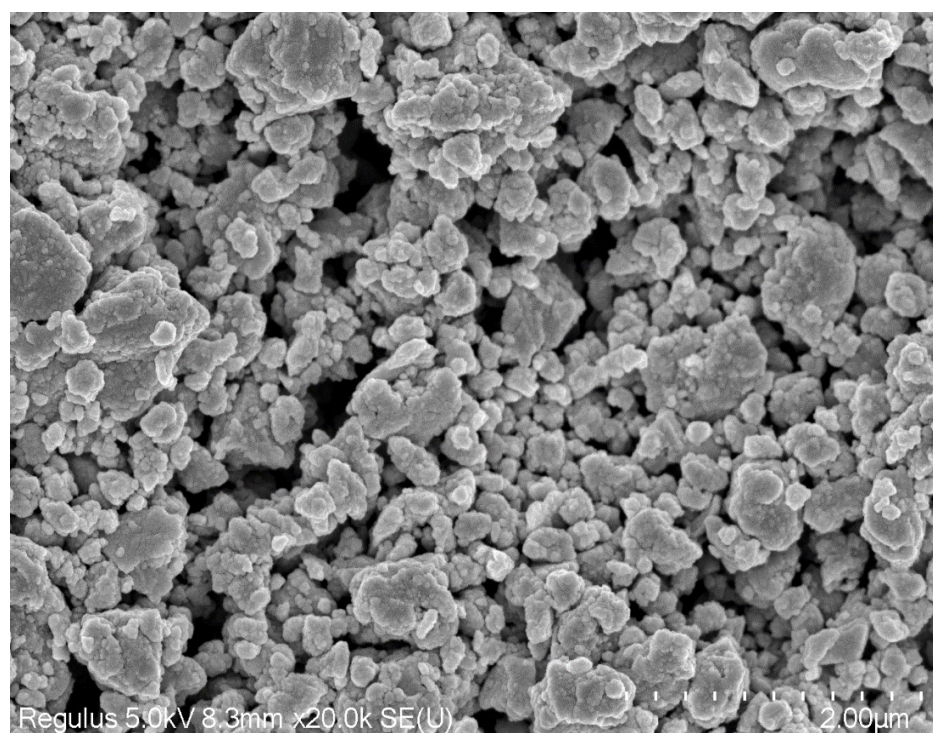
**Figure S1.** SEM image of the TiCe-0.8:0.2-40 sample at the center of the paste region.



**Figure S2.** SEM image of the TiCe-0.2:0.8-40 sample at the center of the paste region.

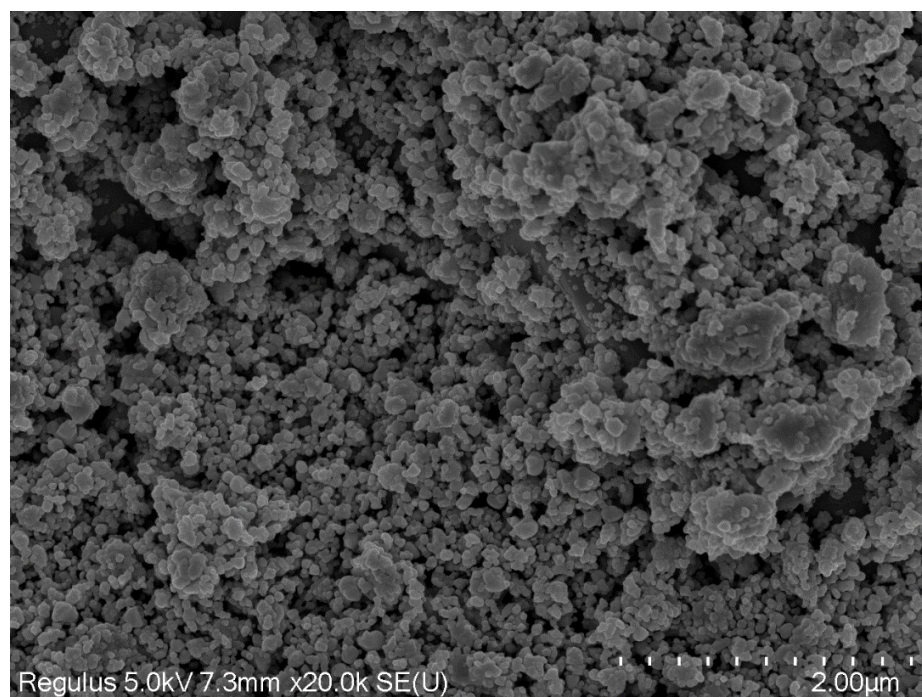


**Figure S3.** SEM image of the TiCe-0.8:0.2-100 sample at the center of the paste region.



**Figure S4.** SEM image of the TiCe-0.2:0.8-100 sample at the center of the paste region.





**Figure S5.** SEM image of the TiCe-0.5:0.5-100 sample at the center of the paste region.